

FDS9933A

Dual P-Channel 2.5V Specified PowerTrench™ MOSFET

General Description

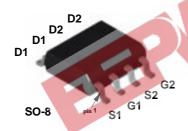
These P-Channel 2.5V specified MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

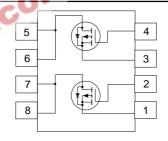
Applications

- Load switch
- DC/DC converter
- Motor drives

Features

- -3.8 A, -20 V. $R_{DS(on)}$ = 0.075 Ω @ V_{GS} = -4.5 V $R_{DS(on)}$ = 0.105 Ω @ V_{GS} = -2.5 V.
- Low gate charge (7nC typical).
- Fast switching speed.
- High performance trench technology for extremely low R_{DS(on)}.
- High power and current handling capability.





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		FDS9933A	Units
V_{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		± 8	V
I _D	Drain Current - Continuous	(Note 1a)	-3.8	Α
	- Pulsed		-20	
P _D	Power Dissipation for Dual Operation		2.0	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1.0	
		(Note 1c)	0.9	
T _J , T _{Sta}	Operating and Storage Junction Temperature Range		-55 to +150	∘C

Thermal Characteristics

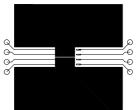
$R_{ heta^JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta^{JC}}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

<u> </u>					
Device Marking	Device	Reel Size	Tape width	Quantity	
FDS9933A	FDS9933A	13"	12mm	2500 units	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics		•			
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-20			V
ABVDSS ATJ	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-16		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V			-1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
	acteristics (Note 2)	V V I 250 A	T 0.4	1 00	1.5	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$	-0.4	-0.8 2.5	-1.5	V mV/∘
<u>A</u> VGS(th) ∧TJ	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}$, Referenced to 25°C		2.5		mv/°
R _{DS(on)}	Static Drain-Source	$V_{GS} = -4.5 \text{ V}, I_D = -3.8 \text{ A}$	a	0.058	0.075	Ω
	On-Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -3.8 \text{ A}, T_J = 125 ^{\circ}\text{C}$		0.086	0.12	Ω
I _{D(on)}	On-State Drain Current	$V_{GS} = -2.5 \text{ V}, I_D = -3.3 \text{ A}$ $V_{GS} = -4.5 \text{ V}, V_{DS} = -5.0 \text{ V}$	-10	0.084	0.105	<u>Ω</u> A
g FS	Forward Transconductance	$V_{DS} = -4.5 \text{ V}, I_{D} = -3.8 \text{ A}$		10		S
Dynamic	Characteristics	The committee				
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1.0 \text{ MHz}$		600		рF
Coss	Output Capacitance			175		рF
C _{rss}	Reverse Transfer Capacitance			80		рF
Switchir	ng Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -5 \text{ V}, I_D = -0.5 \text{ A},$		6	12	ns
t _r	Turn-On Rise Time	V_{GS} = -4.5 V, R_{GEN} = 6.0 Ω		9	18	ns
t _{d(off)}	Turn-Off Delay Time			31	50	ns
t _f	Turn-Off Fall Time			28	42	ns
Qg	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -3.8 \text{ A},$		7	10	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -4.5 V		1.3		nC
Q_{gd}	Gate-Drain Charge			2		nC
Drain-So	ource Diode Characteristic	s and Maximum Ratings				
Is	Maximum Continuous Drain-Sour	ce Diode Forward Current			-1.3	Α
			_	-0.75	-1.2	V

 $R_{\theta,JA}$ is the sum of the junction-to-case and case-to-ambient resistance where the drain pins. $R_{\theta,JC}$ is guaranteed by design while $R_{\theta,JA}$ is determined by the user's board design.





a) 78° C/W when mounted on a 0.5 in² pad of 2 oz. copper.

b) 125° C/W when mounted on a 0.02 in² pad of 2 oz. copper.

c) 135° C/W when mounted on a 0.03 in² pad of 2 oz. copper.



Scale 1 : 1 on letter size paper

2: Pulse Test: Pulse Width $\leq 300~\mu\text{s},~\text{Duty Cycle} \leq 2.0\%$

Typical Characteristics (continued)

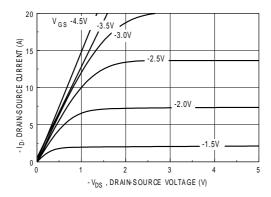


Figure 1. On-Region Characteristics.

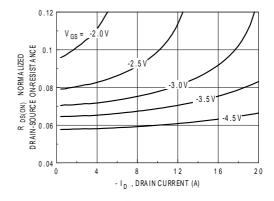


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

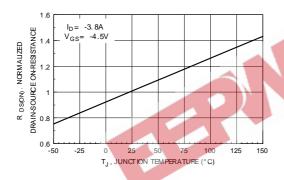


Figure 3. On-Resistance Variation with Temperature.

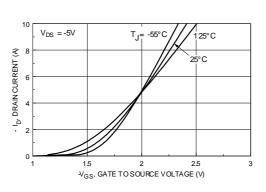


Figure 5. Transfer Characteristics.

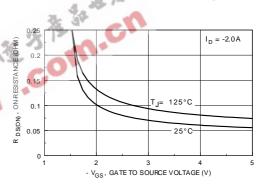


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

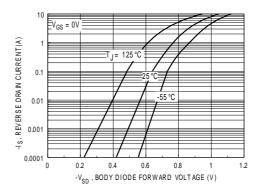
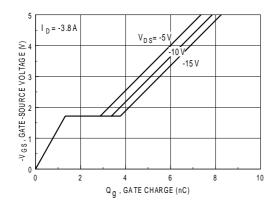


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



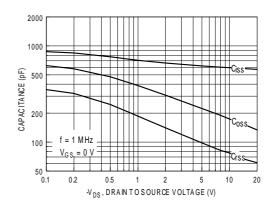
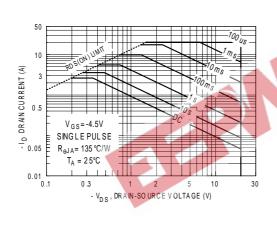


Figure 7. Gate Charge Characteristics.

Figure 8. Capacitance Characteristics.



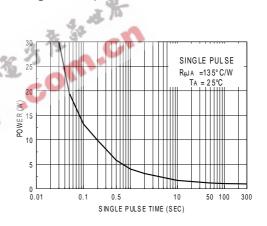


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

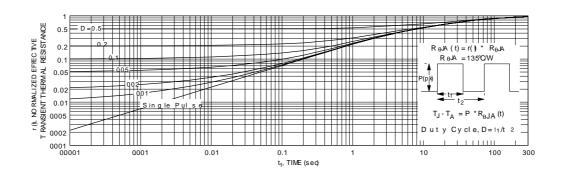
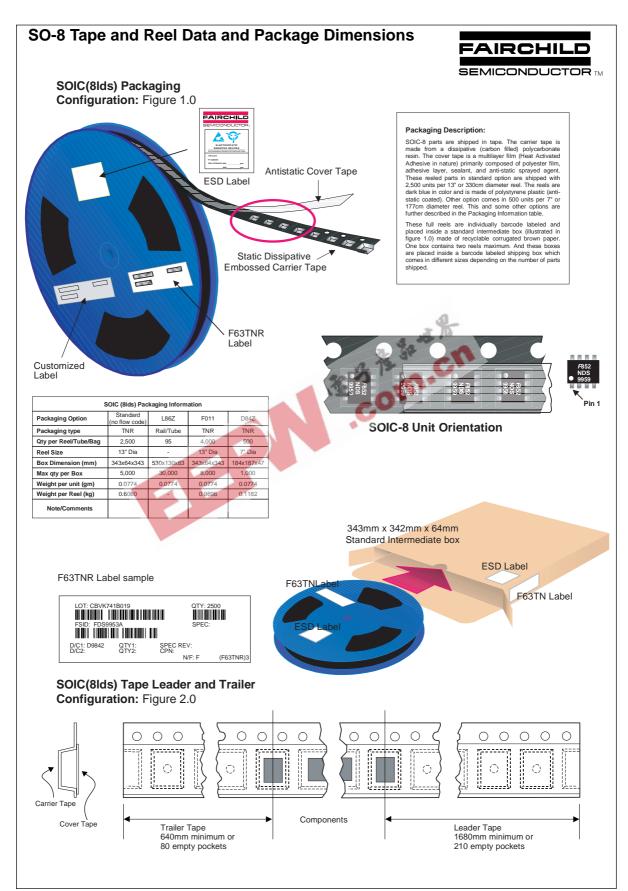
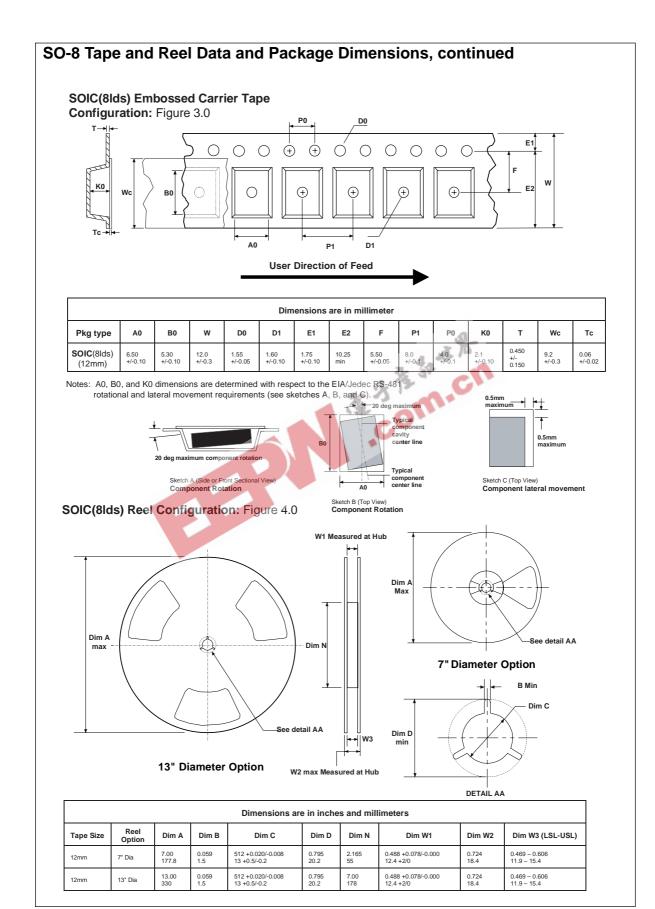
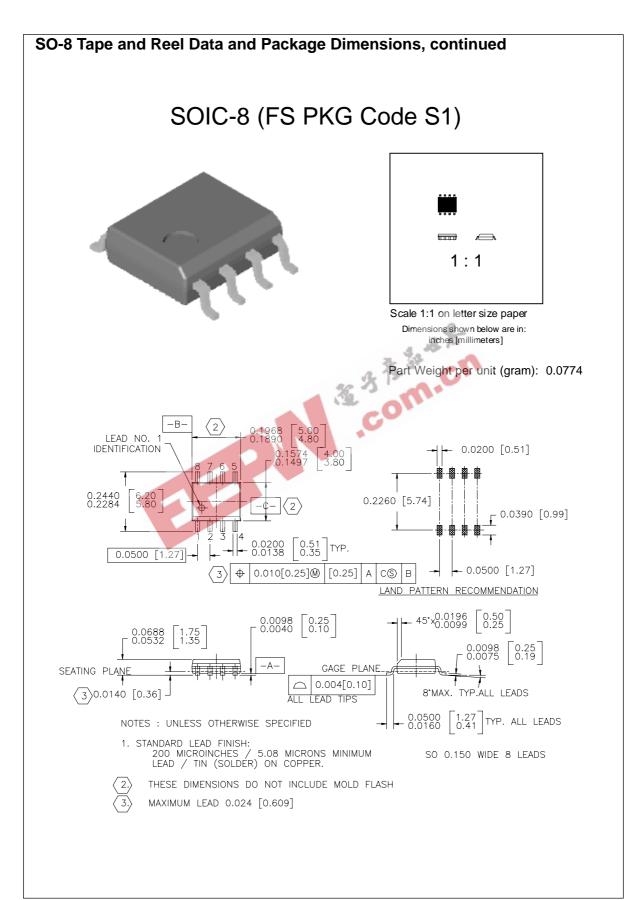


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient themal response will change depending on the circuit board design.







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